



IEEE Defect and Fault Tolerance in VLSI and Nanotechnology Systems Symposium

September 19-20, 2016

University of Connecticut
Storrs, CT USA

SPONSORS



Monday, Sept. 19

8:00-8:30

Registration & Continental Breakfast

8:30-8:45

Opening Remarks by DFT 2016 General and Program Chairs

8:45-9:45

KEYNOTE 1:

Session Chair: Antonio Miele (Politecnico di Milano)

Speaker: Vilas Sridharan, AMD Inc.

Title: Memory Errors in Modern Systems

13:30-14:40

Session 1: Aging

Session Chair: Fabrizio Lombardi (Northeastern U.)

9:45-10:25

(L)* BTI Aware Thermal Management for Reliable DVFS Designs

H. Chahal, V. Tenentes, D. Rossi, and B. Al-Hashimi (U. Southampton)

(S) Prognosis of NBTI Aging Using a Machine Learning Scheme

N. Karimi (Rutgers U.) and K. Huang (San Diego State U.)

(S) Experimental Study and Analysis of Soft and Permanent Errors in Digital Cameras

I. Koren¹, G. Chapman², R. Thomas², R. Thomas² and Z. Koren¹ (¹Univ. of Massachusetts, ²Simon Fraser University)

20 min Coffee Break

Session 2: Fault Tolerance in Latches & Approximate Computing

Session Chair: Naghmeh Karimi (Rutgers U.)

15:00-16:10

10:45-11:45

(L)* A Highly Robust Double Node Upset Tolerant Latch

A. Watkins (Los Alamos National Laboratories) and S. Tragoudas (Southern Illinois University Carbondale)

(L)* Applying Efficient Fault Tolerance to Enable the Preconditioned Conjugate Gradient Solver on Approximate Computing Hardware

A. Schoell, C. Braun and H.-J. Wunderlich (University of Stuttgart)

(S) Construction of A Soft Error (SEU) Hardened Latch with High Critical Charge

H. Ueno and K. Namba (Chiba Univ.)

(S) Design and Analysis of an Approximate 2D Convolver

F. Lombardi (Northeastern U.), J. Han (U. Alberta) and K. Chen (Northeastern U.)

16:20-17:20

17:00-18:30

* Best Paper Candidate

Lunch Break

Session 3: System-level Approaches

Session Chair: Akash Kumar (Technische Universitaet Dresden)

(L) Combined On-line Lifetime-Energy Optimization for Asymmetric Multicores

C. Bolchini (Politecnico di Milano), M. Carminati (Politecnico di Milano), T. Mitra (NUS, Singapore) and T. S. Muthukaruppan (NUS, Singapore)

(L) Effects of Online Fault Detection Mechanisms on Probabilistic Timing Analysis

C. Chen, J. Panerati and G. Beltrame (Ecole Polytechnique de Montreal)

(L) Bounding Error Detection Latency in Safety Critical Systems with Enhanced Execution Fingerprinting

M. Liu and B. Meyer (McGill U.)

(S) Guiding Genetic Algorithms Using Importance Measures for Reliable Design of Embedded Systems

H. Aliee¹, S. Vitzethum¹, M. Glaß¹, J. Teich¹ and ²E. Borgonovo (¹FAU, ²Bocconi U.)

20 min Coffee Break

Session 4: Special Session on Fault-tolerant Realtime Systems

Session Chair: Giovanni Beltrame (Polytechnique Montreal)

(L) Fault-tolerant Scheduling of Multicore Mixed-Criticality Systems under Permanent Failures

Z. Al-Bayati¹, B. H. Meyer¹ and ²H. Zeng (¹McGill U., ²Virginia Tech)

(L) Cross-Layer Fault-Tolerant Design of Real-Time Systems

S. S. Sahoo (NUS, Singapore), B. Veeravalli (NUS, Singapore) and A. Kumar (Technische U. Dresden)

(L) Fault-Aware Sensitivity Analysis for Probabilistic Real-Time Systems

L. Santinelli (ONERA), Z. Guo (UNC) and L. George (LIGM – ESIEE)

Short Break

TPC Meeting

Reception

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| L. Anghel, TIMA, FR | B. Meyer, McGill University, CA |
| C. Bolchini, Politecnico di Milano, IT | M. Mozaffari Kermani, Rochester Inst. Tech., US |
| G. Chapman, Simon Fraser University, US | K. Namba, Chiba University, JP |
| R. Cideciyan, IBM, CH | N. Nicolici, McMaster University, CA |
| A. Daniel, Intel Corporation, US | C. Nicopoulos, University of Cyprus, CY |
| J. Dworak, Southern Methodist University, US | M. Ottavi, Univ. of Rome "Tor Vergata", IT |
| M. Ebrahimi, KTH Royal Inst. Technology, SE | N. Park, Oklahoma State University, US |
| B. Eklow, CISCO, US | I. Polian, University of Passau, DE |
| O. Ergin, TOBB University, TR | L. Pomeranz, Purdue University, US |
| A. Evans, IROC Technologies, FR | S. Pontarelli, Univ. of Rome "Tor Vergata", IT |
| M. Fukushi, Yamaguchi University, JP | M. Psarakis, University of Piraeus, GR |
| D. Gizopoulos, University of Athens, GR | A. Rahmani, Univ. of Turku, FI |
| S. Hamdioui, TU Delft, NL | P. Rech, UFRGS, BR |
| J. Han, University of Alberta, CA | S. Reda, Brown University, US |
| C. Huang, National Tsing Hua University, TW | S. Reddy, University of Iowa, US |
| V. Izosimov, KTH Royal Inst. Technology, SE | P. Reviriego, Universidad Nebrija, ES |
| M. Jenihhin, Tallin Univ. of Technology, EE | D. Rossi, University of Southampton, UK |
| W. Jone, University of Cincinnati, US | F. Salice, Politecnico di Milano, IT |
| P. Joshi, Cadence, US | C. Sandionigi, CEA, FR |
| A. Kanuparthi, Intel Corporation, US | M. Schölzel, Universität Potsdam / IHP, DE |
| N. Karimi, Rutgers University, US | I. Sourdis, Chalmers Univ. of Technology, SE |
| R. Karri, NYU Polytechnic, US | V. Sridharan, AMD, US |
| Y. Kim, Northeastern University, US | M. Tehranipoor, University of Connecticut, US |
| I. Koren, Univ. of Massachusetts-Amherst, US | N. Touba, University of Texas at Austin, US |
| S. Kundu, Univ. of Massachusetts-Amherst, US | S. Tragoudas, S. Illinois Univ Carbondale, US |
| H. Li, Chinese Academy of Science, CN | L. Wang, University of Connecticut, US |
| F. Lombardi, Northeastern University, US | X. Wen, Kyushu Institute of Technology, JP |
| J. Mathew, IIT Patna, IN | D. Xiang, Tsinghua University, CN |
| C. Metra, University of Bologna, IT | |



8:00-8:30

Registration & Continental Breakfast

8:30-9:30

KEYNOTE 2:

Session Chair: Qiaoyan Yu (U. New Hampshire)
 Speaker: Swarup Bhunia, University of Florida
 Title: security versus test and reliability: the crossroads and beyond

9:30-10:30

Session 5: FPGA & CMOS Technologies

Session Chair: Swaroop Ghosh (PSU)

13:30-14:30

- (L) Low Cost Resilient Regular Expression Matching on FPGAs
 M. Leipnitz, E. N. de Souza and G. Nazar (U. Federal do Rio Grande do Sul)
- (L) In-Place LUT Polarity Inversion to Mitigate Soft Errors for FPGAs
 J. Su (UCLA), J.-Y. Lee (UCLA), C. Wu (Fudan U.) and L. He (UCLA, Fudan U.)
- (S) Detecting Intermittent Resistive Faults in Digital CMOS Circuits
 H. Ebrahimi, A. Rohani and H.G. Kerkhoff (U. Twente)
- (S) Soft Error Vulnerability Assessment of the Real-Time Safety-Related ARM Cortex-R5 CPU
 X. Iturbe, B. Venu and E. Ozer (ARM Research)

20 min Coffee Break

Session 6: Architecture-level Techniques

Session Chair: Brett Meyer (McGill U.)

10:50-11:40

- (L) Efficient Utilization of Hierarchical iJTAG Networks for Interrupts Management
 A. Ibrahim (U. Twente) and H. Kerkhoff (U. Twente / CTIT-TDT)
- (S) Error Recovery Through Partial Value Similarity
 A. Eker and O. Ergin (TOBB U. Economics and Technology)
- (S) In-field functional test programs development flow for embedded FPGAs
 R. Cantoro¹, D. Piumatti¹, P. Bernardi¹, S. De Luca² and A. Sansonetti²
 (¹Politecnico di Torino, ²STMicroelectronics)
- (S) Design and characterization of a high-safety hardware/software module for the acquisition of Eurobalise telegram
 F. Giuliani¹, M. Ottavi², G. Cardarilli², M. Re², L. Di Nunzio², R. Fazzolari², A. Bruno¹ and F. Zuliani¹ (¹NEAT S.r.l., ²University of Rome "Tor Vergata")

14:50-16:20

16:20-16:30

Lunch Break

Award Announcement

Session 7: Fault tolerance in NoC & SoC
 Session Chair: Qiaoyan Yu (U. New Hampshire)

- (L) CoBRA: Low Cost Compensation of TSV failures in 3D-NoC
 R. Salamat (UC Irvine), M. Ebrahimi (KTH), N. Bagherzadeh (UC Irvine) and F. Verbeek (Radboud U.)
- (L) A New Approach to Deadlock-Free Fully Adaptive Routing for High-Performance Fault-Tolerant NoCs
 A. Charif, N.-E. Zergainoh and M. Nicolaidis (TIMA Laboratory)
- (S) An Adaptive Routing Algorithm to Improve Lifetime Reliability in NoCs Architecture
 J. Alshraiedeh and A. Kodi (Ohio U.)
- (S) A Novel Method for SEE validation of Complex SoCs Using Low-Energy Proton Beams
 G. Furano¹, S. Di Mascio¹, T. Szweczyk¹, A. Menicucci³, L. Campajola⁴, F. Di Capua⁴, A. Fabbri⁵ and M. Ottavi² (¹European Space Agency, ²U. Rome "Tor Vergata", ³TU Delft, ⁴Naples Federico II, ⁵INFN, Roma Tre Section)

20 min Coffee Break

Session 8: Special Session on the use of VLSI Techniques for Securing ICs against Attacks
 Session Chair: Sandip Kundu (UMass Amherst)

- (L) Reliable PUF Design Using Failure Patterns from Time-Controlled Power Gating
 X. Xu and D. Holcomb (U. Massachusetts, Amherst)
- (L) Side Channel Attacks on STTRAM and Low-Overhead Countermeasures
 A. Iyengar¹, S. Ghosh¹, N. Rathi² and H. Naeimi³ (¹Penn State U., ²Purdue U., ³Intel Corp.)
- (L) On Meta-Obfuscation of Physical Layouts to Conceal Design Characteristics
 V. C. Patil, A. Vijayakumar and S. Kundu (U. Massachusetts Amherst)
- (L) Can Flexible, Domain Specific Programmable Logic Prevent IP Theft?
 X. Cui¹, K. Wu², S. Garg² and R. Karri² (¹Chongqing U., ²NYU)

Closing Remarks